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(54) Title: METHOD AND APPARATUS FOR TESTING A DEVICE-UNDER-TEST

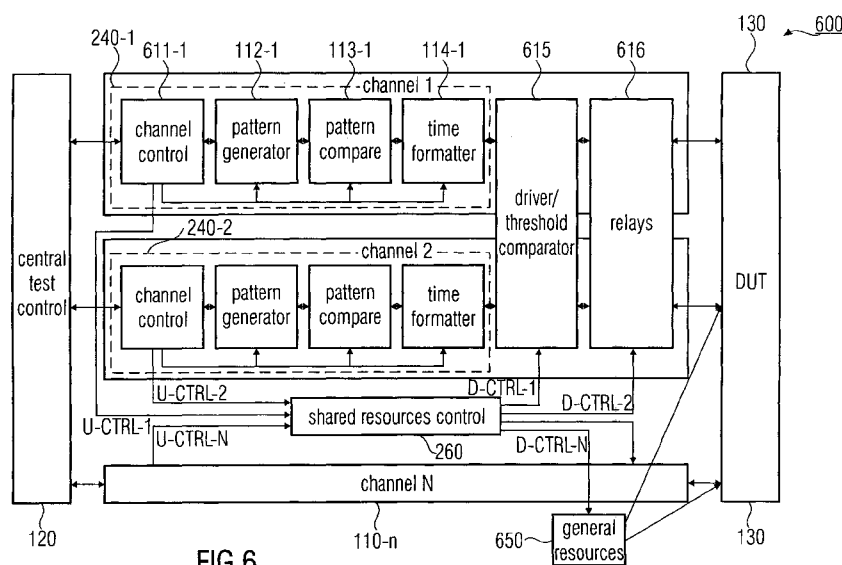


FIG 6

(57) Abstract: Disclosed is a concept for testing a device-under-test (130), the concept comprising receiving, from at least one test channel integrated circuit (240-n) dedicated to communicate with an input or output pin of the device-under-test (130) by means of at least one hardware resource (615; 616), at least one logical control command (U-CTRL-n) describing a desired operation of the at least one hardware resource (150), and converting, by means of a resource control means (260), the at least one logical control command (U-CTRL-n) into at least one dedicated control command (D-CTRL-n) for the at least one hardware resource, wherein the at least one dedicated control command (D-CTRL-n) is adapted to a physical implementation of the at least one hardware resource (615; 616).